# Notice of References Cited

Application/Control No. 10/670,952	Applicant(s)/F Reexamination SCHAFER E			
Examiner	Art Unit			
Stephen A. Holzen	3644	Page 1 of 3		

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	UŞ-3,242,058	03-1966	GANLEY GREGORY J; et. al.	202/176
	В	US-3,708,735	01-1973	Barltrop, Richard Kenneth	318/564
	С	US-4,105,900	08-1978	Martin et al.	327/526
	D	US-4,282,870	08-1981	Porlier, Joseph G. A.	128/203.14
	Ε	US-4,422,180	12-1983	Wendt, Hans J.	398/110
	F	US-4,475,196	10-1984	La Zor, Clair G.	714/46
	G	US-4,895,320	01-1990	Armstrong, Kenneth C.	244/118.5
	Н	US-5,201,830	04-1993	Braswell, Marion M.	244/118.5
	ı	US-5,222,166	06-1993	Weltha, M. Duane	385/24
	J	US-5,273,486	12-1993	Emmons et al.	454/74
	К	US-5,529,265	06-1996	Sakurai, Bunkichi	244/118.5
	L	US-5,677,603	10-1997	Speirs et al.	315/324
	М	US-5,791,982	08-1998	Curry et al.	454/74

### **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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# NON-PATENT DOCUMENTS

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. 10/670,952 Examiner Stephen A. Holzen Applicant(s)/Patent Under Reexamination SCHAFER ET AL. Page 2 of 3

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,809,999	09-1998	Lang, Stephan	128/200.24
	В	US-5,813,630	09-1998	Williams, Kenneth R.	244/118.5
	С	US-5,896,473	04-1999	Kaspari, Daniel K.	385/24
	D	US-5,971,623	10-1999	Wanamaker, Michael F.	385/53
	E	US-6,078,877	06-2000	Fujii et al.	702/188
	F	US-6,216,981	04-2001	Helm, Hagen M	244/118.5
	G	US-6,316,841	11-2001	Weber, Kent	290/4R
	Н	US-6,356,809	03-2002	Morrison et al.	700/286
	ı	US-6,454,209	09-2002	Bock et al.	244/118.5
	J	US-6,401,014	06-2002	Hill et al.	701/3
	к	US-6,491,254	12-2002	Walkinshaw et al.	244/118.5
	L	US-6,527,228	03-2003	Mitani, Hisashi	244/118.5
	М	US-6,561,454	05-2003	White, III, Orland Kermit	244/1R

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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# **NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | SCHAFER ET AL. | Examiner | Art Unit | Page 3 of 3

## **U.S. PATENT DOCUMENTS**

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,664,656	12-2003	Bernier, Alan T.	307/9.1
	В	US-6,666,400	12-2003	White, III, Orland Kermit	244/1R
	С	US-6,719,245	04-2004	Wagner, Wolfgang	244/118.5
	D	US-6,761,628	07-2004	Horner, Darrell W.	454/76
	Е	US-6,817,576	11-2004	Brady et al.	244/118.5
	F	US-6,819,264	11-2004	Bissett, Richard L.	340/945
	G	US-6,824,104	11-2004	Smallhorn, George R.	244/118.5
	Н	US-2003/0132859	07-2003	Bissett, Richard L.	340/945
	1	US-2004/0000616	01-2004	Finke et al.	244/118.5
	J	US-2004/0129835	07-2004	Atkey et al.	244/118.5
	К	US-			
	L	US-			
	М	US-			

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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### **NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.